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Application Number		Based on SN 10/035,441			
Filing Date		Filed: January 4, 2002			
First Named Inventor		Naoki YAMAGUCHI et al.			
Group Art Unit		1763			
Examiner Name		Anita Karen Alanko			
Attorney Docket Number		0756-7191			
Sheet	1	of	3		

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Examiner Initials ¹	Cite No. ¹	U.S. Patent Document		Name of Patent or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
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		Office ²	Number ²	Kind Code ² (if known)			
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials ¹	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ³
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Examiner Signature	<i>calvin</i>	Date Considered	6.20.05
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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